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<p>8 Sheet</p>		<p>1</p>	<p>of</p>	<p>2</p>	<p>Application Number</p> <p>10/511,571</p>
					<p>Filing Date</p> <p>October 12, 2004</p>
					<p>First Named Inventor</p> <p>Paul Frederick Fewster</p>
					<p>Art Unit</p> <p>2882</p>
					<p>Examiner Name</p> <p>Jure E Yun</p>
					<p>Attorney Docket Number</p> <p>5926P037</p>

Examiner Signature	Xerrie Yung	Date Considered	2-28-07
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**Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.*

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Based on PTO/SB/08A (08-03) as modified by Blakely, Sotokoff, Taylor & Zafman (wtr) 08/11/2003.

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				Examiner Name	JURIE YUAN
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
JY.		"Grazing incidence diffraction versus grazing incidence diffraction for strain/stress evaluation in thin films" by ANOUAR NJEH et al.; <i>Powder Diffraction</i> 15 (4), December 2000; pp 211-216	
JY.		"Submicron x-ray diffraction and its applications to problems in materials and environmental science" by N. TAMURA et al.; <i>Review of Scientific Instruments</i> ; Volume 73, Number 3, March 2002; pp. 1369-1372	
JY.		"Submicron X-ray diffraction" by A.A. MacDowell et al.; <i>Nuclear Instruments and Methods in Physics Research A</i> 467-468 (2001); pp. 936-943	
JY.		"Crystallographic Analysis of CVD Films by Using X-Ray Polychromatic Radiation" by B. Lavelle, et al.; 1998 <i>Materials Research Society Symp. Proc.</i> Vol. 524; pp. 121-126	
JY.		"Image Plates as One-Dimensional Detectors in High-Resolution X-ray Diffraction" by A. KINNE et al.; <i>J. Appl. Cryst.</i> (1998); pp. 446-452	
JY.		"Real-time <i>in situ</i> x-ray diffraction as a method to control epitaxial growth" by A.S. BADER et al.; <i>Applied Physics Letters</i> , Volume 82 Number 26; June 30, 2003; pp. 4684-4686	

Examiner Signature	Jeanne Ybarra	Date Considered	2-28-07
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